June 20, 2016

Program of SISS-18 at Seikei University

21st July 2016(Thu.)

- Opening Remarks: 9:55-10:00
- Fundamental, Sputtering: 10:00-12:00

O1-1. (10:00-10:40) -Plenary talk-

Surface and Trace Chemical Analysis using SIMS and Ambient MS for Homeland Security and Forensics

G. Gillen (NIST)

O1-2. (10:40-11:10) -Invited-

SIMS with large gas clusters: Fundamentals, successes and new challenges

A. Delcorrte (Université Catholique de Louvain)

O1-3. (11:10-11:40) -Invited-

High and medium energy backscattering analysis using computer simulation program

T. Nishimura (Hosei University)

O1-4. (11:40-12:00)

Time-of-flight secondary ion mass spectrometry with a vacuum-type electrospray droplet ion gun

S. Ninomiya(University of Yamanashi)

- Lunch: 12:00-13:10
- Organic & Bio-Medical 1: 13:10-15:00

O1-5. (13:10-13:40) -Invited-

Cluster-TOF-SIMS imaging of lipids and metabolites in tissue

A. Brunelle (Institut de Chimie des Substances Naturelles)

O1-6. (13:40-14:10) -Invited-

Lipidomic imaging with a new hybrid 3D SIMS molecular imaging instrument

M. K. Passarelli (NPL)

O1-7. (14:10-14:40) -Invited-

Drug screening by ToF-SIMS technique

Tae Geol Lee (KRISS)

O1-8. (14:40-15:00)

Evaluation of blood adsorption on artificial kidney using TOF-SIMS

S. Aoyagi (Seikei University)

- Coffee break: 15:00-15:15
- Sponsored session: 15:15-16:35

O1-9. (15:15-15:35)

Recent developments on Cameca SIMS and Atom Probe

F. Horréard (AMETEK-CAMECA)

O1-10. (15:35-15:55)

Recent Topics in TOF-SIMS Instrumentation at ULVAC-PHI

S. Iida (ULVAC-PHI)

O1-11. (15:55-16:15)

Latest application on TOYAMA Laser-SNMS

A. Takano(Toyama)

O1-12. (16:15-16:35)

From Surface Spectrometry to 3D Analysis - Latest Trends and Instrumentation for TOF-SIMS

M. Terhorst (ION-TOF GmbH)

- Short presentation: 16:35-17:05
- Poster session: 17:15-18:15
- Reception: 18:15-20:00

<u>22nd July 2016(Fri.)</u>

- Organic & Bio-Medical 2: 9:30-10:50

O2-1. (9:30-10:00) -Invited-

Cell and Tissue applications of the NanoSIMS 50L in medicine and pharmacology

F. Horréard (AMETEK-CAMECA)

O2-2. (10:00-10:30) -Invited-

Analyses of freeze-fixed plant samples by cryo-TOF-SIMS

D. Aoki (Nagoya University)

O2-3. (10:30-10:50)

Kendrick Mass Defect Analysis for High-Resolution Mass Spectrometry and the Possibility of the Application to SIMS

M. Fujii (AIST)

- Coffee break: 10:50-11:05

- Instrumentation & application 1: 11:05-12:05

O2-4. (11:05-11:35) -Invited-

SIMS imaging on the Helium Ion Microscope

J. N. Audinot (Luxembourg Institute of Science and Technology)

O2-5. (11:35-12:05) -Invited-

Precision of oxygen two isotope SIMS analysis using IMS-1280

G. Tang (Chinese Academy of Science)

- Lunch: 12:05-13:15
- Atom probe session: 13:15-15:00

O2-6. (13:15-13:45) -Invited-

Impact of atom probe tomography to the development of rare earth permanent magnets

K. Hono (NIMS)

O2-7. (13:45-14:15) -Invited-

Challenge of hydrogen distribution analysis for semiconductor devices by several techniques, APT, SIMS and ERDA

A. Kuramoto (Toshiba)

O2-8. (14:15-14:35)

Reconstruction of Atom Probe Tomography by using FEM

Yun Kim (University of Tokyo)

- Coffee break: 14:35-14:50
- Instrumentation & application 2: 14:50-16:40

O2-9. (14:50-15:20) -Invited-

Biological Imaging Beyond “Show & Tell”:Sub-Micron Imaging and Identification of Molecular Chemistry by TOF-SIMS Parallel Imaging MS/MS

G. L. Fisher (Physical Electronics)

O2-10. (15:20-15:40)

Development of New Cluster-SIMS Instrument Combined with Tandem Mass Spectrometer

K. Suzuki (Kyoto University)

O2-11. (15:40-16:00)

Dual Beam Depth Profiling with Clusters: Comparison between Ar, O_2, and SF_6 Gas Cluster Ion Bombardment

D. Rading (ION-TOF GmbH)

O2-12. (16:00-16:20)

Mass spectrometric analysis of the dissociative scattering of argon cluster ions from solid surfaces

K. Moritani (University of Hyogo)

O2-13. (16:20-16:40)

A new approach of interface analysis: measurement of benzoic acid in solution using ambient SIMS

M. Kusakari (Kyoto University)

- Closing Remarks:16:40-16:45